

FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: PEK-In1137 Appl. No.:	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant: JOSEF FAZEKAS ET AL.	
		Filing Date: August 25, 2003 Group Art Unit:	

EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>SLR</i>	A 5,777,486	7/7/98	Hsu			
	B					
	C					
	D					
	E					
	F					
	G					
	H					
	I					

## FOREIGN PATENT DOCUMENT

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
<i>SLR</i>	J 06077299	3/18/94	Japan			
<i>SLR</i>	K 2000003947	1/7/00	Japan			
<i>SLR</i>	L 2000174085	6/23/00	Japan			
<i>SLR</i>	M 0 448 273 A1	9/25/91	Europe			
	N					

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>SLR</i>	Schafft, H. A.: "Reliability Test Chips: NIST 33 & NIST 34 for JEDEC Inter-Laboratory Experiments and More", 97 IRW Final Report, pp. 144 and 145
<i>SLR</i>	Sriram, T. S.: "Electromigration Test Structure Designed to Identify via Failure Modes", IEEE, 2000, pp. 155-157

EXAMINER	DATE CONSIDERED
<i>Slemon-ag-Hsu</i>	<i>8/6/04</i>